

# Empirical Study on the Burn-in Time of SDRAM Products

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## Abstract

This study focuses on a burn-in test carried out on SDRAM products for the purpose of obtaining reliability and optimal burn-in time and test costs. The empirical analysis results of this study show that the lifetime of SDRAM products conforms to a Weibull distribution.

Keyword : Accelerated Life Testing, burn-in test, reliability test, reliability objective model.